Notice of References Cited

_	Application/Control No. 09/687,401	Applicant(s)/Patent Under Reexamination MANGER ET AL.		
	Examiner	Art Unit	_	
	Arlen Soderquist	1743	Page 1 of 2	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,915,652	10-1975	Natelson, Samuel	422/65
	В	US-5,496,009	03-1996	Farrell et al.	251/61.1
	С	US-5,571,410	11-1996	Swedberg et al.	210/198.2
	D	US-2002/0037499	03-2002	Quake et al.	435/5
	Ε	US-6,408,878	06-2002	Unger et al.	137/597
	F	US-6,533,914	03-2003	Liu, Shaorong	204/601
	G	US-6,563,111	05-2003	Moon et al.	250/288
	Н	US-6,605,472	08-2003	Skinner et al.	436/171
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				·	
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Schomburg, W. K. et al, Proceedings of the 12th European Conference on Solid-State Transducers, Southampton, UK, Sept. 13-16, 1998, Volume 1, 711-714, Editor: White, N. M Institute of Physics Publishing, Bristol, UK.
	V	Hosokawa, K. et al, IEEE International Conference on Micro Electro Mechanical Systems, Technical Digest, 12th, Orlando, FL, Jan. 17-21, 1999, 388-393, Institute of Electrical and Electronics Engineers, New York, N. Y.
	w_	Ericson, C. et al, Analytical Chemistry 2000, 72, 81-87.
	x	Kawano, Y. et al, FEMS Microbiology Letters 2000, 189, 103-108.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No. 09/687,401	Reexamination	Applicant(s)/Patent Under Reexamination MANGER ET AL.			
Examiner	Art Unit				
Arlen Soderquist	1743	Page 2 of 2			

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Ā	US-			
	В	US-			
	С	US-			
	D	US-		*	
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

	· · · · · · · · · · · · · · · · · · ·					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q				·	
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Xu, J. et al, Analytical Chemistry 2000, 72, 1930-1933.
	V	Anderson, J. R. et al, Analytical Chemistry 2000, 72), 3158-3164.
	w	Shinohara, J. et al, Annual International Conference on Micro Electro Mechanical Systems, Proceedings, 13th, Miyazaki, Japan, Jan. 23-27, 2000, 86-91 Institute of Electrical and Electronics Engineers, New York, N. Y.
	x	Quake, S. R. et al, Science 2000, 290, 1536-1540.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.